Abstracts

Reliability Testing of Microwave Transistors for Array-Radar Applications

B.C. Dodson, Jr. and W.H. Weisenberger. "Reliability Testing of Microwave Transistors for Array-Radar Applications." 1974 Transactions on Microwave Theory and Techniques 22.12 (Dec. 1974, Part II [T-MTT] (1974 Symposium Issue)): 1239-1246.

Solid-state array radar is of great current interest because of the inherent reliability of solid-state devices and the concomitant promise for improvement in system reliability. However, no extensive reliability base has been established for solid-state devices employed under radar operating requirements. In this paper some of the important factors bearing a device reliability are treated. Accelerated life tests under RF conditions are presented for L-band power transistors. Preliminary life-test and failure-analysis data are also presented with recommendations on how the information can be used by the radar systems designer.

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